

PHOTONICS DEVICE MAPPING PROBE TESTER MODEL 58212-C

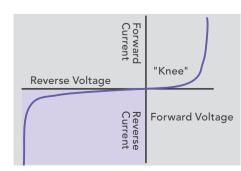
Chroma 58212-C is an automated Epitaxial Wafer/Chip probe test system with precision temperature-control that provides fast and accurate optoelectronic performance measurements and multi-site tests for a wide range of Laser Diode and Light-Emitting Diode (LED) product applications.

The 58212-C probe tester features a flexible design that provides testing for different types of optoelectronic components, including Lateral, Vertical, and Flip Chip. The pretest scan program provides complete wafer mapping to ensure test accuracy, while our patented probe tip prevents scratching of the DUT and ensures that every chip contact is made properly.

Chroma 58212-C's customized multi-site design supports testing multiple locations in a single probe, stabilizes the test, saves test time and increases test performance.

At the same time, optical data such as forward current, forward voltage, leakage current, reverse breakdown voltage, slope efficiency, and photoelectric conversion efficiency can be obtained all in one single probe.

The 58212-C's software interface and advanced logic algorithms significantly improve production efficiency. Comprehensive test reports and yield statistics allow users to easily get a handle on production.



I-V Curve

MODEL 58212-C

KEY FEATURES

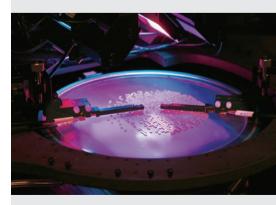
- High-speed and high-precision testing
- Supports lateral, vertical and flip-chip configurations
- Up to 8 inch wafers
- Wide range of electrical tests (LD or LED)
- Accurate and fast alignment scanning process
- Multi-site test functionality
- Auto load/unload

Measurement Items

- Electrical measurements:
 - Threshold Current (Ith)
 - Forward Voltage (Vf)
 - Reverse Leakage Current (Ir)
 - Reverse Breakdown Voltage (Vbr)
- Optical measurements:
 - Optical Power
 - Centre Wavelength (Wc)
 - Peak Wavelength (Wp)
 - Full Width at Half Maximum (FWHM)

Hardware

- Automated LED wafer/chip prober
- Electical test module
- Optical test module
- Optional ESD test module (LED applications)





SPECIFICATIONS

Model		58212-C
Application		
Test Area		ψ 8 inch wafer
Wafer Size		Chip on wafer: 2", 4", 6", 8"
		Chip on tape : 2", 4", 6"
Chuck Type (A chuck is decided by a device type)		Lateral type, Vertical type, and Flip chip type (select one of them)
Die Size		6 ~ 120mil
Pad Size		≥ 50μm
Operating Temperature		25°C ~85°C / 0°C ~100°C
Electrical Measurements		
Measurement Items		Threshold Current (Ith), Forward Voltage (Vf), Reverse leakage Current (Ir),
		Reverse Breakdown Voltage (Vrb)
Current Range		\pm 6A (\leq 5V & Pulse Mode Only), \pm 3.5A (\leq 5V), \pm 2.5A(\leq 10V), \pm 1A,
		±100mA, ±10mA, ±1mA, ±100μA, ±10μA, ±1μA
Driving Mode		CW and Pulsing
Pulse Width		Min.100µs (depending on the DUT, pulse width may need to be longer to
		have stable voltage and power readings)
Duty Cycle		< 10% (when I=2.5A \sim 3.5A, pulse width \leq 5ms, voltage<5V)
		(Heat dissipation affects the pulse duty cycle constraint)
Optical Measurements		
Measurement Items		Optical Power, Centre Wavelength (Wc), Peak Wavelength (Wp),
		Full Width at Half Maximum (FWHM)
Optical Power	Range	0.5mW~500mW
	Repeatability	≦3%
Wavelength	Range	UVC to NIR (Further discussion is possible on other ranges)
	Repeatability (FWHM)	≦ ± 0.3nm
Facility Requirements		
Machine Dimension		1160mm (L) x 1240mm (W) x 1500mm (H)
Power Requirement		Single phase, 220VAC ±10%, 50/60Hz, 20A
Input Air		-0.2 Mpa / ψ6 mm
Weight		750 kg
Environment	Temperature	20°C ~ 30°C
	Humidity	40% ~ 70%

^{*} All specifications are subject to change without notice.

ORDERING INFORMATION

58212-C: Photonics Device Mapping Probe Tester

Get more product & global distributor information in Chroma ATE APP







Search Keyword

58212-C

HEADQUARTERS CHROMA ATE INC. 88 Wenmao Rd., Guishan Dist., Taoyuan City 333001, Taiwan T +886-3-327-9999 F +886-3-327-8898 www.chromaate.com info@chromaate.com U.S.A. CHROMA ATE, INC. (U.S.A.) 7 Chrysler, Irvine, CA 92618 T +1-949-421-0355 F +1-949-421-0353 Toll Free +1-800-478-2026 www.chromaus.com info@chromaus.com

EUROPE CHROMA ATE EUROPE B.V. Morsestraat 32, 6716 AH Ede,The Netherlands T +31-318-648282 F +31-318-648288 www.chromaeu.com salesnl@chromaeu.com

CHROMA ATE GERMANY Südtiroler Str. 9, 86165, Augsburg, Germany T +49-821-790967-0 F +49-821-790967-600 www.chromaeu.com salesde@chromaeu.com JAPAN
CHROMA JAPAN
CORP.
888 Nippa-cho,
Kouhoku-ku,
Yokohama-shi,
Kanagawa,
223-0057 Japan
T +81-45-542-1118
F +81-45-542-1080
www.chroma.co.jp
info@chroma.co.jp

KOREA CHROMA ATE KOREA BRANCH 3F Richtogether Center, 14, Pangyoyeok-ro 192, Bundang-gu, Seongnam-si, Gyeonggi-do 13524, Korea T +82-31-8017-6614 www.chromaate.com info@chromaate.com

CHINA
CHROMA ATE
(SUZHOU) CO., LTD.
Building 7, ShiShan
Industrial Gallery,
No. 855, Zhu Jiang Rd.,
Suzhou New District,
Jiang Su, China
T +86-512-6824-5425
F +86-512-6824-0732

SOUTHEAST ASIA
QUANTEL PTE LTD.
(A company of Chroma Group)
25 Kallang Avenue #05-02
Singapore 339416
T +65-6745-3200
F +65-6745-9764
www.quantel-global.com
sales@quantel-global.com